

Notice of References Cited	Application/Control No. 10/565,323		Applicant(s)/Patent Under Reexamination SAWADA ET AL.	
	Examiner Bijan Ahvazi		Art Unit 4171	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0144319 A1	07-2006	Sawada et al.	117/002
	B	US-			
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	D	US-			
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	I	US-			
	J	US-			
	K	US-			
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	M	US-			

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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